# **MOSFET** - Power, Single

# **N-Channel**

80 V, 13.4 mΩ, 41 A

# **NVTFS6H854NL**

#### **Features**

- Small Footprint (3.3 x 3.3 mm) for Compact Design
- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- NVTFS6H854NLWF Wettable Flanks Product
- AEC-Q101 Qualified and PPAP Capable
- These Devices are Pb-Free and are RoHS Compliant

## **MAXIMUM RATINGS** (T<sub>J</sub> = 25°C unless otherwise noted)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			$V_{DSS}$	80	V
Gate-to-Source Voltage	9		V <sub>GS</sub>	±20	V
Continuous Drain		T <sub>C</sub> = 25°C	I <sub>D</sub>	41	Α
Current R <sub>θJC</sub> (Notes 1, 2, 3, 4)	Steady	T <sub>C</sub> = 100°C	1	29	
Power Dissipation	State	T <sub>C</sub> = 25°C	$P_{D}$	54	W
R <sub>θJC</sub> (Notes 1, 2, 3)		T <sub>C</sub> = 100°C		27	
Continuous Drain		T <sub>A</sub> = 25°C	I <sub>D</sub>	10	Α
Current R <sub>0JA</sub> (Notes 1, 3, 4)	Steady	T <sub>A</sub> = 100°C		7	
Power Dissipation	State	T <sub>A</sub> = 25°C	P <sub>D</sub>	3.2	W
R <sub>θJA</sub> (Notes 1, 3)		T <sub>A</sub> = 100°C		1.6	
Pulsed Drain Current	$T_A = 25$	°C, t <sub>p</sub> = 10 μs	I <sub>DM</sub>	182	Α
Operating Junction and Range	Storage T	emperature	T <sub>J</sub> , T <sub>stg</sub>	-55 to +175	°C
Source Current (Body Diode)			Is	45	Α
Single Pulse Drain-to-Source Avalanche Energy (I <sub>L(pk)</sub> = 2.2 A)			E <sub>AS</sub>	168	mJ
Lead Temperature for S (1/8" from case for 10 s)		urposes	TL	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

#### THERMAL RESISTANCE MAXIMUM RATINGS (Note 1)

Parameter	Symbol	Value	Unit
Junction-to-Case - Steady State (Note 3)	$R_{\theta JC}$	2.8	°C/W
Junction-to-Ambient - Steady State (Note 3)	$R_{\theta JA}$	47	

- The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
- 2. Psi  $(\Psi)$  is used as required per JESD51-12 for packages in which substantially less than 100% of the heat flows to single case surface.
- 3. Surface-mounted on FR4 board using a 650 mm<sup>2</sup>, 2 oz. Cu pad.
- Continuous DC current rating. Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.

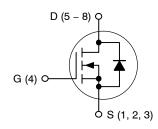


## ON Semiconductor®

#### www.onsemi.com

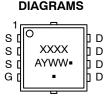
V <sub>(BR)DSS</sub>	R <sub>DS(ON)</sub> MAX	I <sub>D</sub> MAX	
90.1/	13.4 mΩ @ 10 V	44.0	
80 V	17.3 mΩ @ 4.5 V	41 A	

#### N-Channel





<sup>1</sup>
WDFN8
(μ8FL)
CASE 511AB



**MARKING** 



WDFNW8 (Full-Cut μ8FL) CASE 515AN



XXXX = Specific Device Code A = Assembly Location

Y = Year
WW = Work Week
Pb-Free Package

(Note: Microdot may be in either location)

#### **ORDERING INFORMATION**

See detailed ordering, marking and shipping information in the package dimensions section on page 5 of this data sheet.

# **ELECTRICAL CHARACTERISTICS** ( $T_J = 25^{\circ}C$ unless otherwise noted)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS	•				•	•	
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		80			V
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{GS} = 0 \text{ V},$ $T_J = 25^{\circ}\text{C}$				10	μΑ
			T <sub>J</sub> = 125°C			100	
Gate-to-Source Leakage Current	I <sub>GSS</sub>	V <sub>DS</sub> = 0 V, V <sub>G</sub>	<sub>S</sub> = 20 V			100	nA
ON CHARACTERISTICS (Note 5)	•			•	•	•	
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}, I_{D}$	= 45 μΑ	1.2		2.0	V
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V, I <sub>I</sub>	<sub>O</sub> = 10 A		11.1	13.4	mΩ
		V <sub>GS</sub> = 4.5 V, I	<sub>D</sub> = 10 A		13.8	17.3	
Forward Transconductance	9 <sub>FS</sub>	V <sub>DS</sub> = 15 V, I <sub>I</sub>	<sub>0</sub> = 20 A		56		S
CHARGES AND CAPACITANCES		•		<u>I</u>	1		
Input Capacitance	C <sub>iss</sub>				902		pF
Output Capacitance	C <sub>oss</sub>	V <sub>GS</sub> = 0 V, f =	1 MHz,		118		1
Reverse Transfer Capacitance	C <sub>rss</sub>	V <sub>DS</sub> = 40 V			7		
Total Gate Charge	Q <sub>G(TOT)</sub>	V <sub>GS</sub> = 10 V, V <sub>DS</sub> = 40 V, I <sub>D</sub> = 20 A			17		nC
Threshold Gate Charge	Q <sub>G(TH)</sub>				2		
Gate-to-Source Charge	Q <sub>GS</sub>	1			3.0		
Gate-to-Drain Charge	$Q_{GD}$	$V_{GS} = 4.5 \text{ V}, V_{DS} = 40 \text{ V}, I_D = 20 \text{ A}$			2.9		
Plateau Voltage	V <sub>GP</sub>				3.0		V
Total Gate Charge	Q <sub>G(TOT)</sub>	1			8		nC
SWITCHING CHARACTERISTICS (N	ote 6)			<u>.</u>	1		.1
Turn-On Delay Time	t <sub>d(on)</sub>				10		ns
Rise Time	t <sub>r</sub>	V <sub>GS</sub> = 4.5 V, V <sub>E</sub>	ne = 64 V.		36		
Turn-Off Delay Time	t <sub>d(off)</sub>	I <sub>D</sub> = 20 A, R <sub>G</sub>	$= 2.5 \Omega$		17		
Fall Time	t <sub>f</sub>				6		
DRAIN-SOURCE DIODE CHARACTE	RISTICS	•		<u>I</u>	1		
Forward Diode Voltage	$V_{SD}$	V <sub>GS</sub> = 0 V,	T <sub>J</sub> = 25°C		0.82	1.2	V
		I <sub>S</sub> = 10 A	T <sub>J</sub> = 125°C		0.68		1
Reverse Recovery Time	t <sub>RR</sub>		1		32	<u> </u>	ns
Charge Time	t <sub>a</sub>	V <sub>GS</sub> = 0 V, dl <sub>S</sub> /dt	= 100 A/us		20		1
Discharge Time	t <sub>b</sub>	$I_{S} = 20$	Α		12		1
Reverse Recovery Charge	Q <sub>RR</sub>	1			25	<u> </u>	nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

5. Pulse Test: Pulse Width ≤ 300 µs, Duty Cycle ≤ 2%.

6. Switching characteristics are independent of operating junction temperatures.

#### **TYPICAL CHARACTERISTICS**

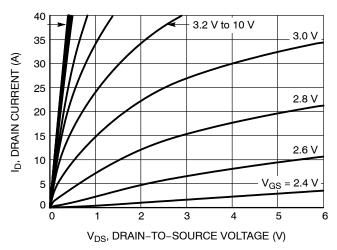


Figure 1. On-Region Characteristics

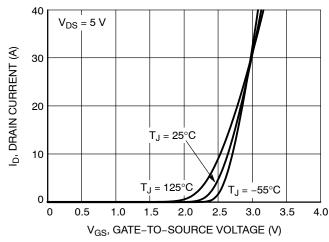


Figure 2. Transfer Characteristics

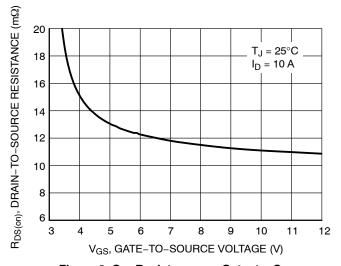


Figure 3. On-Resistance vs. Gate-to-Source Voltage

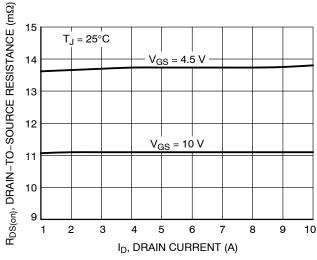


Figure 4. On-Resistance vs. Drain Current and Gate Voltage

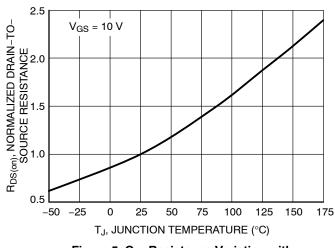


Figure 5. On–Resistance Variation with Temperature

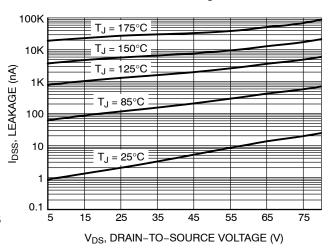


Figure 6. Drain-to-Source Leakage Current vs. Voltage

#### **TYPICAL CHARACTERISTICS**

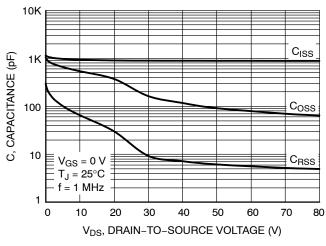


Figure 7. Capacitance Variation

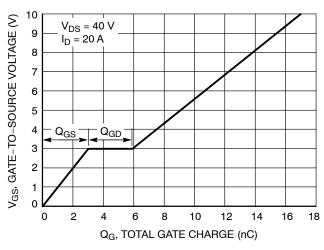


Figure 8. Gate-to-Source vs. Total Charge

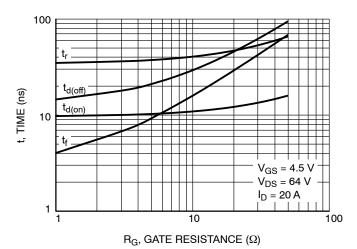


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

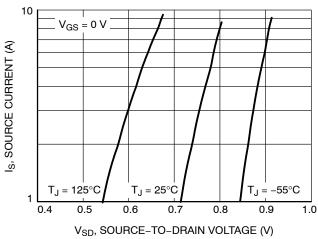


Figure 10. Diode Forward Voltage vs. Current

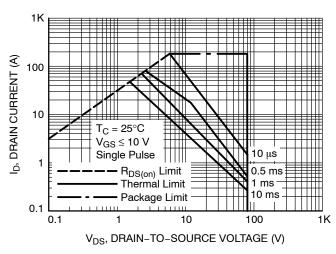


Figure 11. Maximum Rated Forward Biased Safe Operating Area

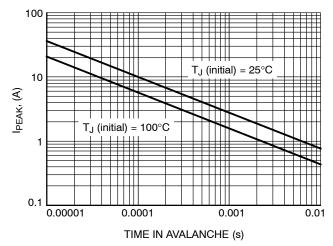


Figure 12. Maximum Drain Current vs. Time in Avalanche

#### **TYPICAL CHARACTERISTICS**

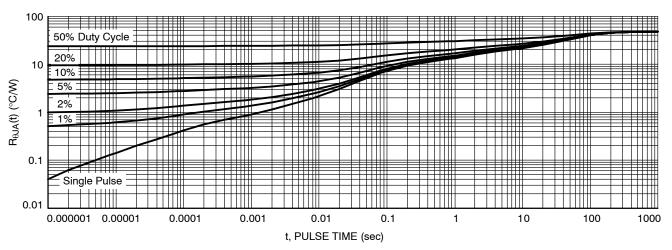


Figure 13. Thermal Response

## **DEVICE ORDERING INFORMATION**

Device	Marking	Package	Shipping <sup>†</sup>
NVTFS6H854NLTAG	854L	WDFN8 (Pb-Free)	1500 / Tape & Reel
NVTFS6H854NLWFTAG	54LW	WDFN8 (Pb-Free, Wettable Flanks)	1500 / Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.



#### WDFN8 3.3x3.3, 0.65P CASE 511AB ISSUE D

**DATE 23 APR 2012** 



#### NOTES:

- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
  CONTROLLING DIMENSION: MILLIMETERS.
  DIMENSION D1 AND E1 DO NOT INCLUDE MOLD FLASH
  PROTRUSIONS OR GATE BURRS.

	MI	MILLIMETERS			INCHES	
DIM	MIN	NOM	MAX	MIN	NOM	MAX
Α	0.70	0.75	0.80	0.028	0.030	0.031
A1	0.00		0.05	0.000		0.002
b	0.23	0.30	0.40	0.009	0.012	0.016
С	0.15	0.20	0.25	0.006	0.008	0.010
D		3.30 BSC		0	.130 BSC	;
D1	2.95	3.05	3.15	0.116	0.120	0.124
D2	1.98	2.11	2.24	0.078	0.083	0.088
E		3.30 BSC		0	.130 BSC	;
E1	2.95	3.05	3.15	0.116	0.120	0.124
E2	1.47	1.60	1.73	0.058	0.063	0.068
E3	0.23	0.30	0.40	0.009	0.012	0.016
е	0.65 BSC			(	0.026 BS	0
G	0.30	0.41	0.51	0.012	0.016	0.020
K	0.65	0.80	0.95	0.026	0.032	0.037
L	0.30	0.43	0.56	0.012	0.017	0.022
L1	0.06	0.13	0.20	0.002	0.005	0.008
М	1.40	1.50	1.60	0.055	0.059	0.063
θ	0 °		12 °	0 °		12 °



#### **GENERIC MARKING DIAGRAM\***

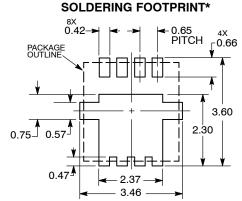


XXXXX = Specific Device Code = Assembly Location

= Year WW = Work Week = Pb-Free Package

\*This information is generic. Please refer to device data sheet for actual part marking.

Pb-Free indicator, "G" or microdot " ■", may or may not be present.



DIMENSION: MILLIMETERS

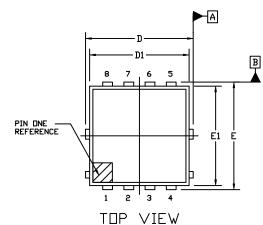
\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

DOCUMENT NUMBER:	98AON30561E	Electronic versions are uncontrolled except when accessed directly from the Document Repositor Printed versions are uncontrolled except when stamped "CONTROLLED COPY" in red.		
DESCRIPTION:	WDFN8 3.3X3.3, 0.65P		PAGE 1 OF 1	

ON Semiconductor and un are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. ON Semiconductor does not convey any license under its patent rights nor the rights of others.



**DATE 25 AUG 2020** 



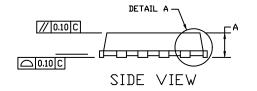


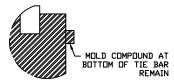
#### NDTES:

- 1. DIMENSIONING AND TOLERANCING PERASME Y14.5M, 2009.
- 2. CONTROLLING DIMENSION: MILLIMETERS
- DIMENSION D1 AND E1 D0 NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR GATE BURRS.

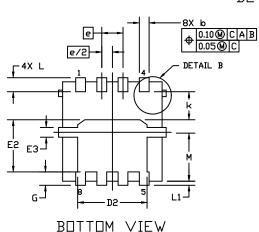
	PLATED AREA
DETAIL	C C SEATING PLANE

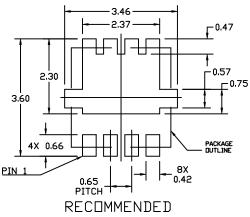
	MILLIMETERS			
DIM	MIN.	NDM.	MAX.	
A	0.70	0.75	0.80	
A1	0.00		0.05	
ø	0.23	0.30	0.40	
n	0.15	0.20	0.25	
D	3.05	3.30	3.55	
D1	2.95	3.05	3.15	
D2	1.98	2.11	2.24	
Ε	3.05	3.30	3.55	
E1	2.95	3.05	3.15	
E2	1.47	1.60	1.73	
E3	0.23	0.30	0.40	
a		0.65 BSC		
G	0.30	0.41	0.51	
K	0.65	0.80	0.95	
٦	0.30	0.43	0.59	
L1	0.06	0.13	0.20	
М	1.40	1.50	1.60	





DETAIL B





MOUNTING FOOTPRINT

For additional information on our Pb-Free strategy and soldering details, please download the DN Semiconductor Soldering and Mounting Techniques Reference Manual, SDLDERRM/D.

# GENERIC MARKING DIAGRAM\*



XXXX = Specific Device Code

A = Assembly Location

Y = Year

WW = Work Week

= Pb-Free Package

\*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "•", may or may not be present. Some products may not follow the Generic Marking.

(Note: Microdot may be in either location)

DOCUMENT NUMBER:	98AON24556H	Electronic versions are uncontrolled except when accessed directly from the Document Reposit Printed versions are uncontrolled except when stamped "CONTROLLED COPY" in red.		
DESCRIPTION:	WDFNW8 3.3x3.3, 0.65P (F	WDFNW8 3.3x3.3, 0.65P (Full-Cut μ8FL WF)		

ON Semiconductor and are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. ON Semiconductor does not convey any license under its patent rights nor the rights of others.

onsemi, ONSEMI, and other names, marks, and brands are registered and/or common law trademarks of Semiconductor Components Industries, LLC dba "onsemi" or its affiliates and/or subsidiaries in the United States and/or other countries. onsemi owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of onsemi's product/patent coverage may be accessed at <a href="www.onsemi.com/site/pdf/Patent-Marking.pdf">www.onsemi.com/site/pdf/Patent-Marking.pdf</a>. Onsemi reserves the right to make changes at any time to any products or information herein, without notice. The information herein is provided "as-is" and onsemi makes no warranty, representation or guarantee regarding the accuracy of the information, product features, availability, functionality, or suitability of its products for any particular purpose, nor does onsemi assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using onsemi products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications provided by onsemi. "Typical" parameters which may be provided in onsemi data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. onsemi does not convey any license under any of its intellectual property rights nor the rights of others. onsemi products are not designed, intended, or authorized for use as a critical component in life support systems or any EDA class 3 medical devices or medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer pu

#### **PUBLICATION ORDERING INFORMATION**

LITERATURE FULFILLMENT: Email Requests to: orderlit@onsemi.com

onsemi Website: www.onsemi.com

TECHNICAL SUPPORT North American Technical Support: Voice Mail: 1 800-282-9855 Toll Free USA/Canada Phone: 011 421 33 790 2910

Europe, Middle East and Africa Technical Support:

Phone: 00421 33 790 2910

For additional information, please contact your local Sales Representative